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·				Application Number	09/781,833		
	ORMATION I			Filing Date	February 12, 2001	AFR	
STA	TEMENT BY	APPLI	CANT	First Named Inventor	Eldridge et al.	1	/I/Pa
•	(use as many sheets	as necessar	ry)	Group Art Unit	1765	APR -	
				Examiner Name	A. Alanko	P 8	ONNY
Sheet	1	of	2	Attorney Docket No.	276440-4	C 75	775
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Examiner Initials*	Cite No. 1	U.S. Pater	nt Document Kind Code <sup>2</sup>	Name of Patentee or Applicant	Publication Date	Relevant Portions		
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Examiner Initials*	Cite No. <sup>1</sup>	Forei	gn Patent Docum Number <sup>4</sup> Kind	nent l Code <sup>5</sup>	Name of Patentee or Applicant	Publication Date	Relevant Portions	Te
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Examiner		Date		/ i	
Signature	Anta Glerner	Considered	61	12/03	<b>&gt;</b>

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 2 of 2

<u> </u>	Modified Form P	TO/SB/08A
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Application Number	09/781,833	RES
Filing Date	February 12, 2001	CENT
First Named Inventor	Eldridge et al.	APP
Group Art Unit	1765	
Examiner Name	A. Alanko	70 50 MAZ
Attorney Docket No.	276440-4	700

	OTH	IER PRIOR ART – NONPATENT LITERATURE DOCUMENTS	-
Examiner Initials <sup>†</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>6</sup>
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Signature	Auta Hanko	Considered	6/2/03

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<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

FORM PTO-1449 (MODIFIED)

ATTY. DOCKET NO.
276440-4

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

(USE SEVERAL SHEETS IF NECESSARY)

ATTY. DOCKET NO.
276440-4

O9/781,833

APPLICANTS:
Benjamin N. ELDRIDGE and Stuart W. WENZEL

FILING DATE: February 12, 2001

GROUP: 2812 1765

Reference Designation

Reference Designation

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Initial	Document Number	Date	Name	Class	Subclass if appropriate
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## lectronic Information Disclosure Statement

# Method For Forming Microelectronic Spring Structures On A Substrate

Application:

Confirmation: 8560

Applicant(s): Benjamin Eldridge

Docket

276440-4

**Group Art** 

Number:

1765

Examiner:

Unit:

A. Alanko

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Note: Applicant is not required to submit a paper copy of cited US Patent Documents

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### **Signature**

Examiner Name	Date
Anita Hanko	6/2/03